Docket No: 740756-2660

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re l	New Patent Application of)	
Shinji	MAEKAWA)	·
Japan	ese Priority Application No. 2002-303659) Att	n: Applications
Japan	ese Priority Date: October 17, 2002)	Branch
For:	METHOD OF MANUFACTURING)	
	SEMICONDUCTOR DEVICE) Dat	te: October 16, 2003

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

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In accordance with the duty of disclosure as set forth in 37 C.F.R. §1.56, Applicants hereby submit the following information in conformance with 37 C.F.R. §§ 1.97 and 1.98. Pursuant to 37 C.F.R. § 1.98, a copy of each of the documents cited is enclosed.

Japanese Patent Application Laid-Open No. 07-130652 is in the same family as U.S. Patents 5,643,826 and 5,923,962 and European Patent 0 651 431 A2.

Japanese Patent Application Laid-Open No. 07-161634 is in the same family as U.S. Patents 5,543,352 and 5,612,250.

Japanese Patent Application Laid-Open No. 2001-345453 is in the same family as U.S. Patent Application Publication No. US2001/0052950 A1.

Japanese Patent Application Laid-Open No. 2001-85703 is in the same family as U.S. Patent 6,426,245 B1 and U.S. Publication No. US2002/0146874A1.

Japanese Patent Application Laid-Open No. 08-228006 is in the same family as U.S. Patent 5,953,597.

It is requested that the accompanying PTO-1449 be considered and made of record in the above-identified application. To assist the Examiner, the

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documents are listed on the attached form PTO-1449. It is respectfully requested that an Examiner initialed copy of this form be returned to the undersigned.

Respectfully submitted,

By:

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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Complete if Known		
			LOSURE	Application Number	New Application	
				Filing Date	October 16, 2003	
(use as many sheets as necessary)		First Named Inventor	Shinji MAEKAWA			
		Art Unit				
		Examiner Name				
Sheet	1	of	1	Attorney Docket Number	740756-2660	

			U.S. PATENT DOCUME	ENTS	
Examiner Initials	Cite No. ¹	U.S. Patent Document	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where
		Number - Kind Code ² (if known)	MM-DD-YYYY	Applicant of Cited Document	Relevant Passages or Relevant Figures Appear
		US-5,643,826	07/01/1997	Ohtani et al.	
		US-5,923,962	07/13/1999	Ohtani et al.	
		US-5,543,352	08/06/1996	Ohtani et al.	
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		F	OREIGN PATENT D	OCUMENTS		
Examiner Initials*	Cite No.1	Foreign Patent Document	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where Relevant Passages or Relevant	
		Country Code ³ Number ⁴ (if known)	MM-DD-YYYY	Application of Cited Document	Figures Appear	T ₆
		JP 07-130652	05/19/1995	Otani et al.		Abstract
	-	EP 0 651 431 A2	05/03/1995	Ohtani et al.		Full
		JP 07-161634	06/23/1995	Otani et al.		Abstract
		JP 2001-345453	12/14/2001	Yamazaki et al.		Abstract
		JP2001-85703	03/30/2001	Kawasaki et al.		Abstract
		JP 08/228006	09/03/1996	Kusumoto et al.		Abstract
		OTHER PRIOR	ART – NON PATENT I	LITERATURE DOCUMENTS		
Examiner Initials				T ²		
Kazuhiro SHIMIZU et al., "High-Mobility Poly-Si Thin-Film Transistors Fabricated Novel Excimer Laser Crystallization Method", IEEE TRANSACTIONS ON ELECT DEVICES., VOL. 40, NO. 1, pp. 112-117.						

Examiner	Date
Signature	Considered

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.